



US00D921502S

(12) **United States Design Patent** (10) **Patent No.:** **US D921,502 S**
Wang (45) **Date of Patent:** **** Jun. 8, 2021**

(54) **TEMPERATURE PROBE**

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(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (13) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/58**

(58) **Field of Classification Search**
USPC D10/52, 53, 57, 58, 60
CPC . G01K 1/024; G01K 1/08; G01K 1/14; B65D 85/38

See application file for complete search history.

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Primary Examiner — Leanne Was-Englehart

(57) **CLAIM**

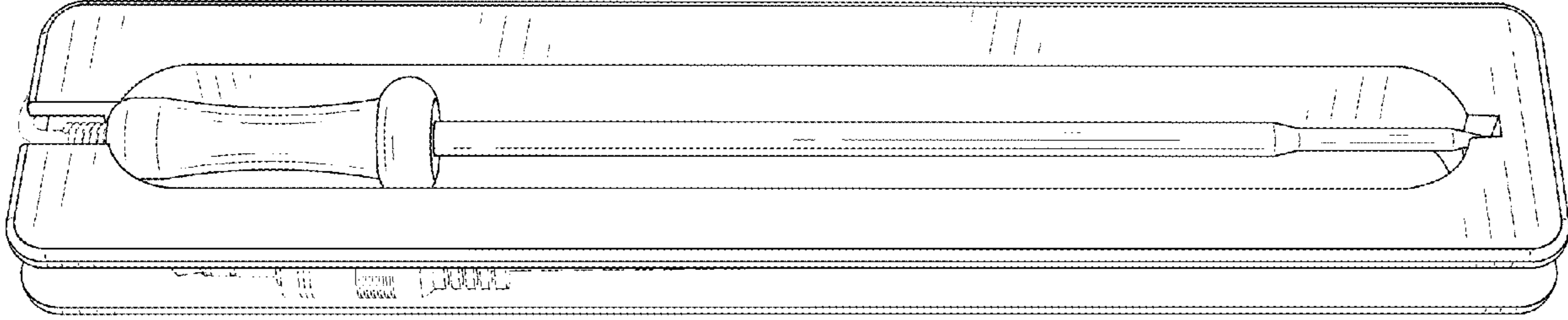
The ornamental design for a temperature probe, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of a temperature probe showing my new design;
 FIG. 2 is a front elevational view thereof;
 FIG. 3 is a rear elevational view thereof;
 FIG. 4 is a left side elevational view thereof;
 FIG. 5 is a right side elevational view thereof;
 FIG. 6 is a top plan view thereof; and,
 FIG. 7 is a bottom plan view thereof.

The broken lines in the drawings depict portions of the temperature probe that form no part of the claimed design.

1 Claim, 7 Drawing Sheets



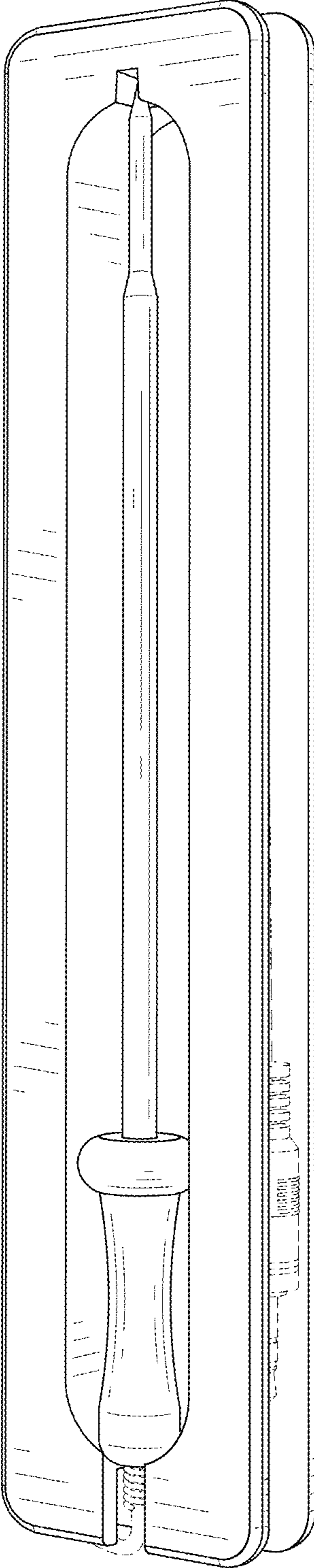


FIG. 1

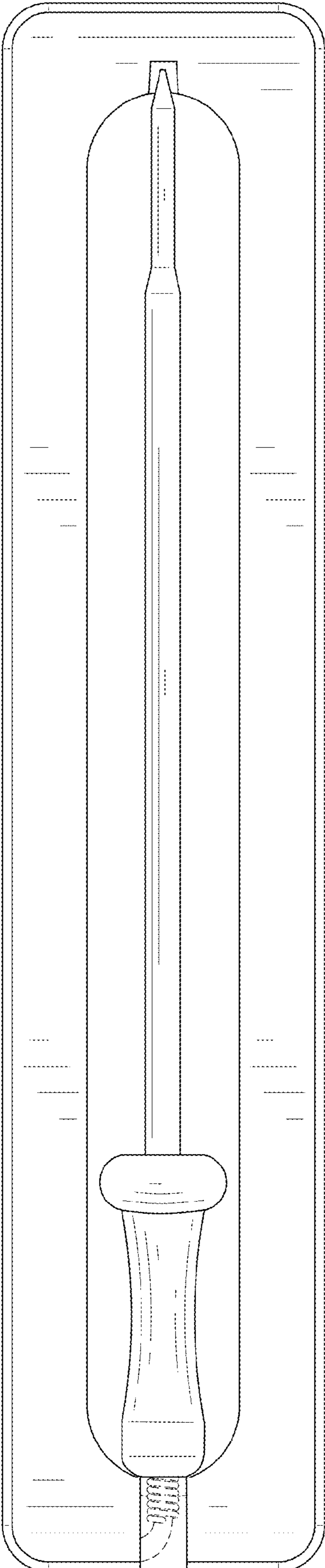


FIG. 2

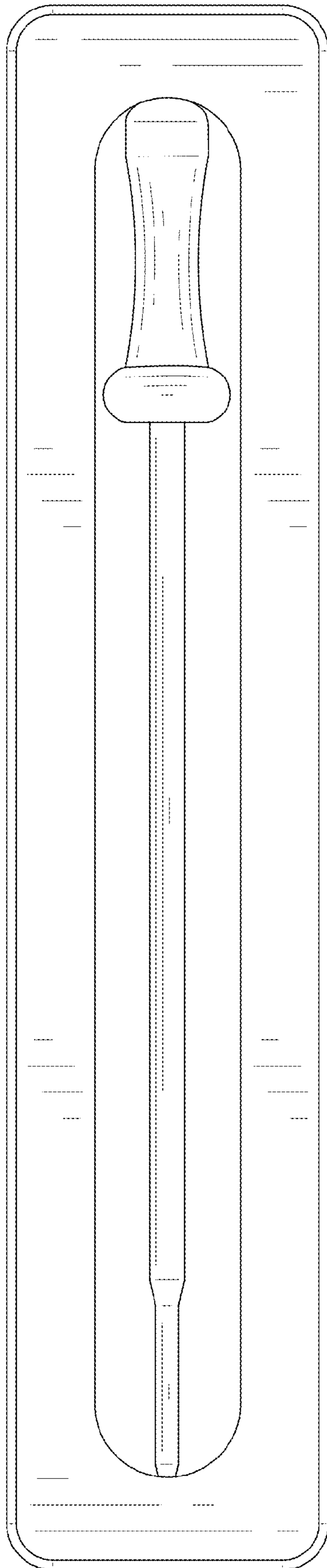


FIG. 3

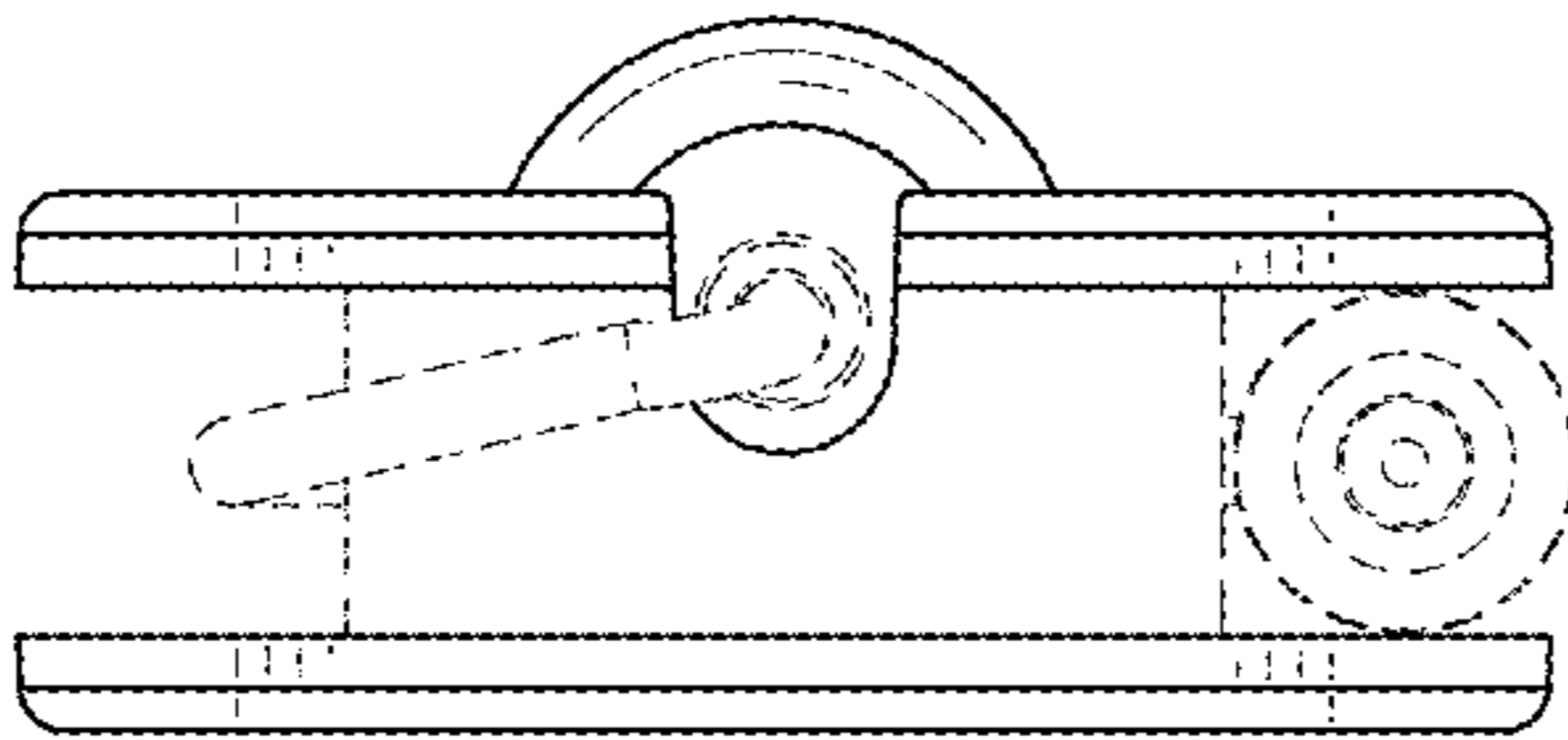


FIG. 4

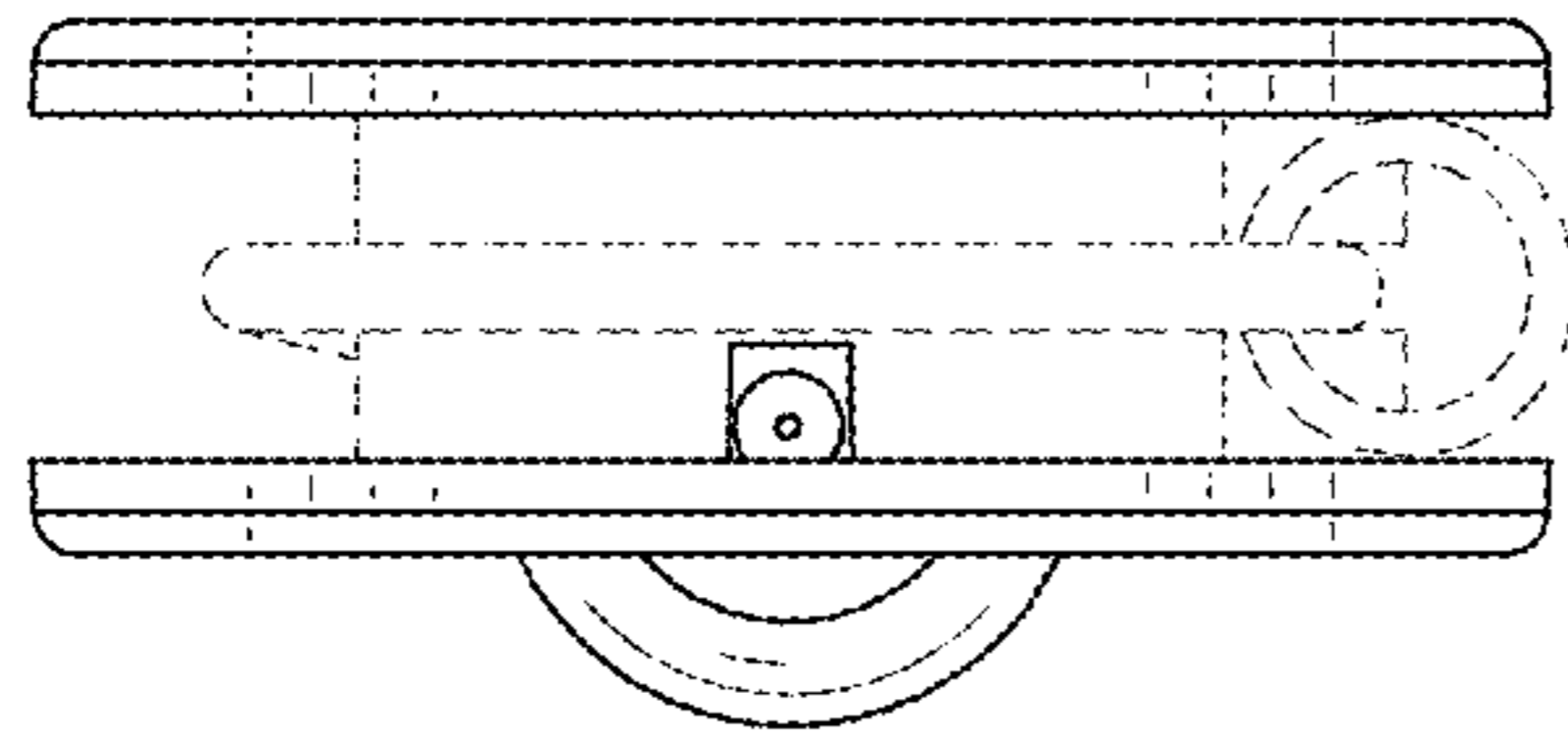


FIG. 5

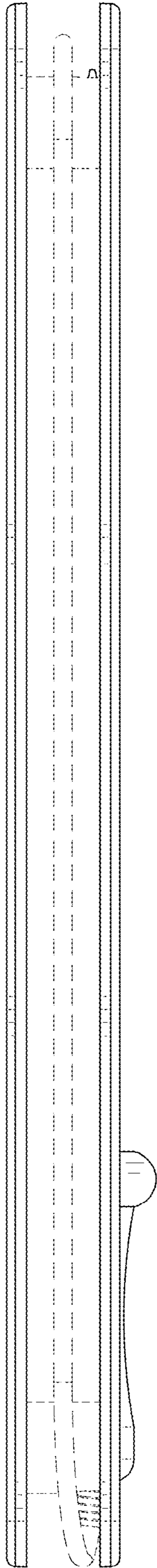


FIG. 6

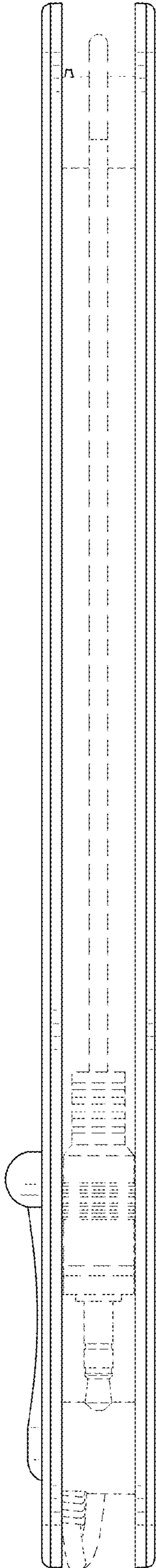


FIG. 7